

Date	User	Film	Recipe	Dep.time	Thickness	JAW EC-400 (Woolam S. E.)		Avg Index	Index+1%	Index -1%	Dep. Rate	Avg.dep. rate			HF e.r.	Stress	Avg. Stress	Avg+10%	Avg-10%	LPD (light point defects)		Comment	Mike Silva
						Index @ 632.8nm	Index @ 1550nm					rate	Avg+10%	Avg-10%						LPD before deposition	LPD after deposition		
01/01/14	User	SIN	1_SINDep	(sec)	(Å)						(nm/min)	(nm/min)	(nm/min)	(nm/min)	(nm/min)	(MPa)	(MPa)	(MPa)	(MPa)				
Nitride																							
01/09/14	Bilja	SIN	in_dep	900	617.69	1.962	1.955	1.972	2.031	1.913	4.12	4.13	4.55	3.72	14.53	-1721.22	-1583.23	-1741.56	-1424.91	80	15039	Failed, 1st run	1/8/2014 cryo req.complete
01/09/14	Bilja	SIN	in_dep	900	592.91	1.962	1.969	1.972	2.031	1.913	3.95	4.13	4.55	3.72			-1583.23	-1741.56	-1424.91	68	4755	Particles in the center of wafer, 2nd run	
01/31/14	Bilja	SIN	in_dep	900	585.66	1.948	1.945	1.972	2.031	1.913	3.90	4.13	4.55	3.72	26.48	-1552.92	-1583.23	-1741.56	-1424.91				
03/19/14	Bilja	SIN	in_dep	900	662.23	1.996	1.979	1.972	2.031	1.913	4.41	4.13	4.55	3.72	6.03	-1570.39	-1583.23	-1741.56	-1424.91	89	662		
04/09/14	Bilja	SIN	in_dep	900	640.38	1.993	1.978	1.972	2.031	1.913	4.27	4.13	4.55	3.72	4.92	-1488.40	-1583.23	-1741.56	-1424.91	133	1602		

Thickness	619.77	Avg HF e.r.	12.99
Avg. Index	1.972	Avg Stress	-1583.23
Avg+3%	2.031	Avg+10%	-1741.56
Avg-3%	1.913	Avg-10%	-1424.91
Avg. Dep. Rate	4.13		
Avg+10%	4.55		
Avg-10%	3.72		

